

<b>Notice of References Cited</b>	Application/Control No. 10/016,630	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,148,346 A	11-2000	Hanson, Gordon L.	719/321
	B	US-6,607,314 B1	08-2003	McCannon et al.	400/62
	C	US-6,324,521 B1	11-2001	Shiota et al.	705/27
	D	US-6,788,428 B1	09-2004	Shimokawa, Katsumi	358/1.15
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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